

Device Modeling Report

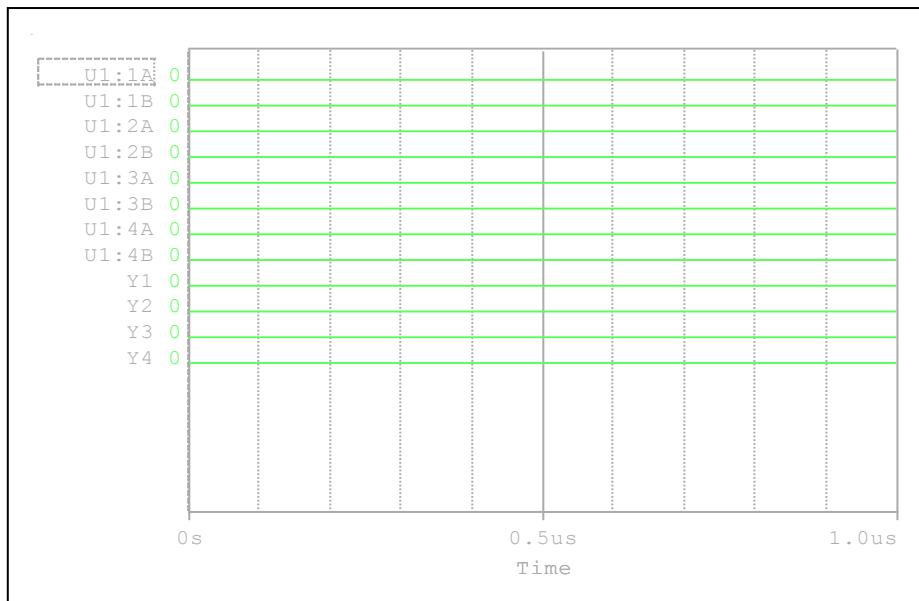
COMPONENTS : CMOS DIGITAL INTEGRATED CIRCUIT
PART NUMBER : TC74AC08FT
MANUFACTURER : TOSHIBA



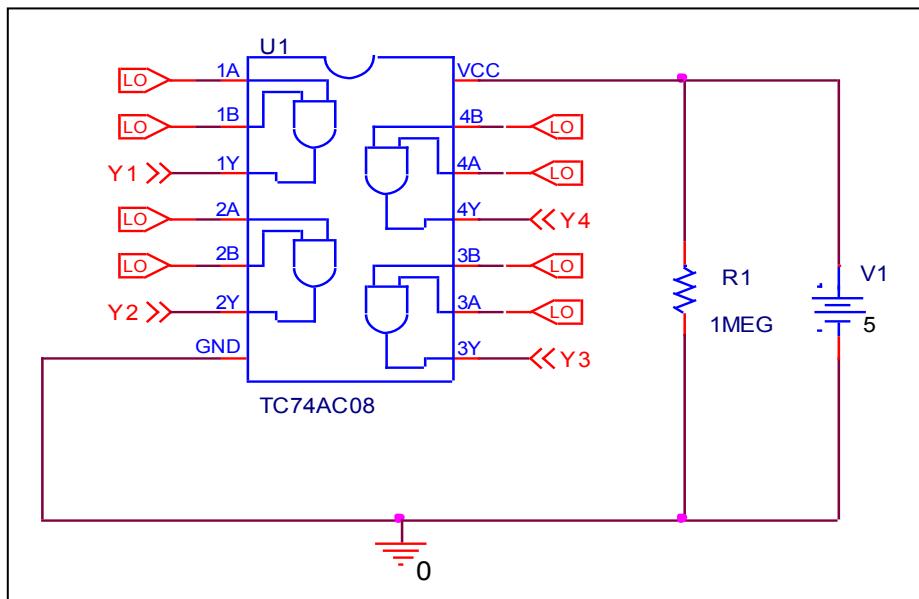
Bee Technologies Inc.

Truth Table

Circuit simulation result



Evaluation circuit

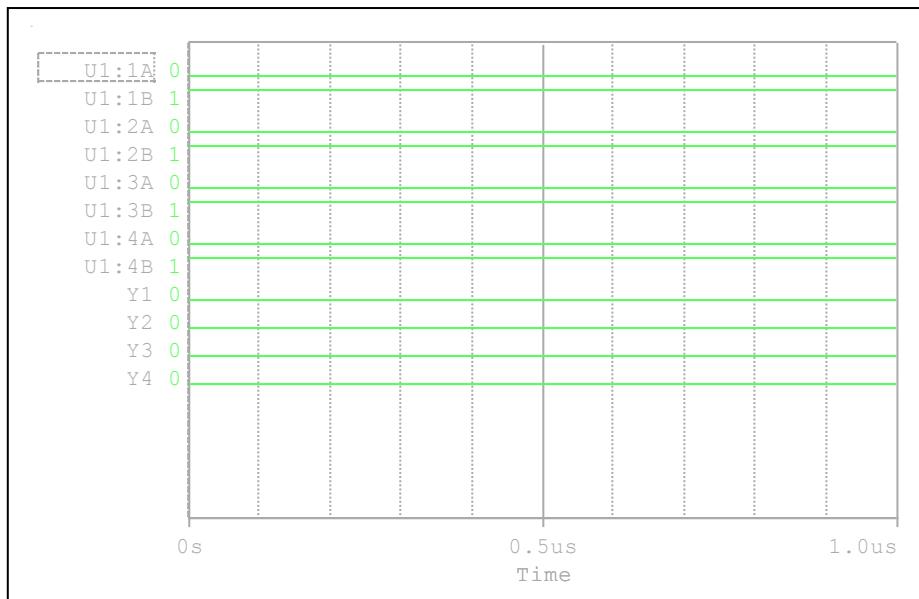


Comparison table

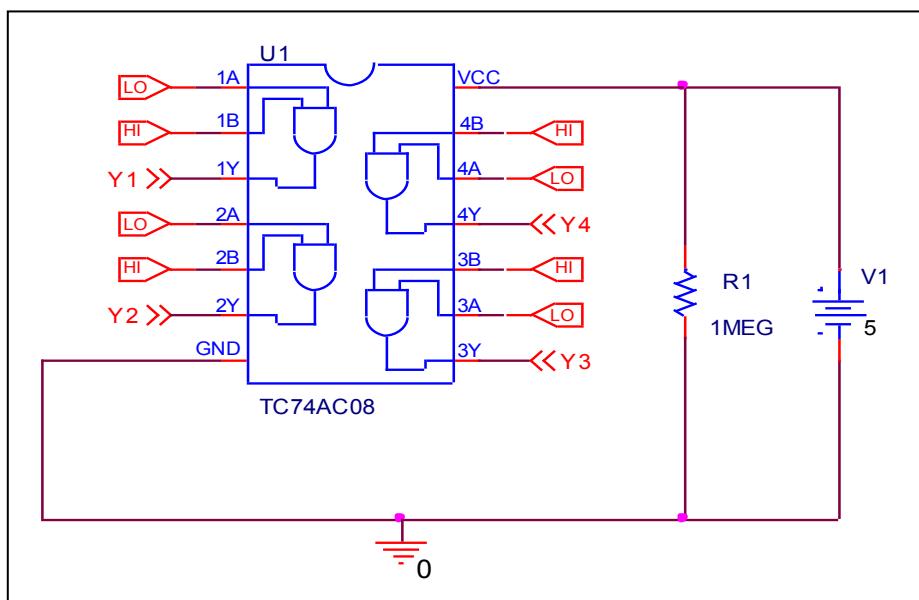
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
L	L	L	L	0

Truth Table

Circuit simulation result



Evaluation circuit

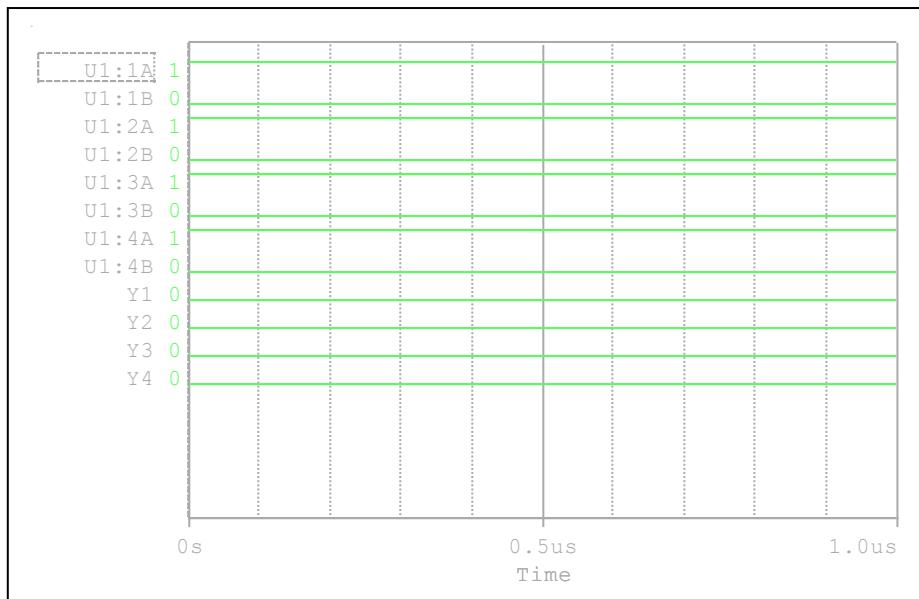


Comparison table

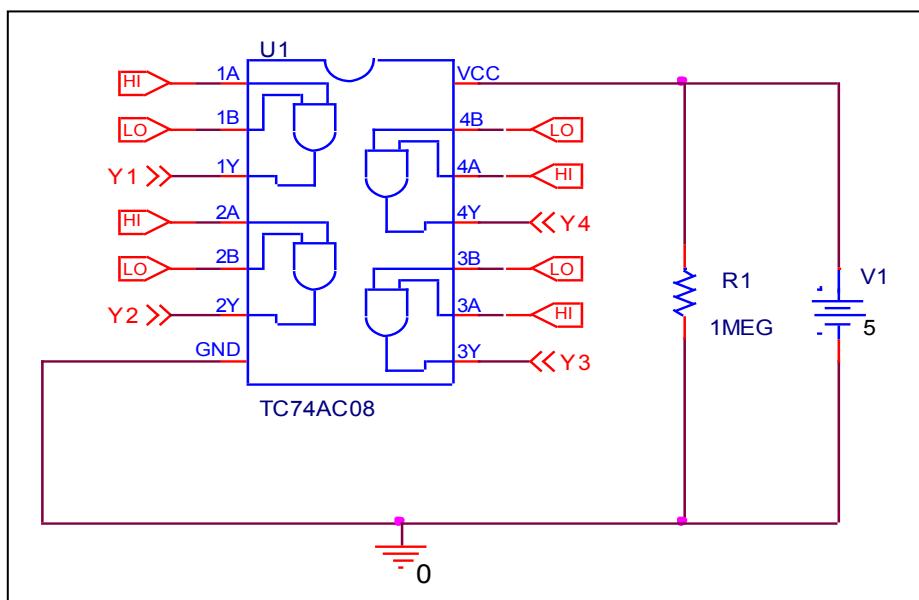
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
L	H	L	L	0

Truth Table

Circuit simulation result



Evaluation circuit

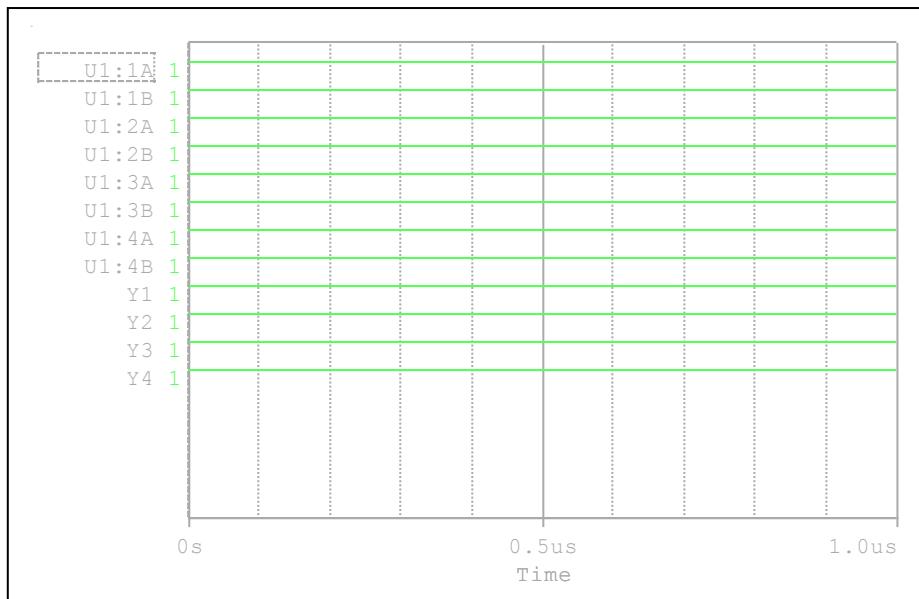


Comparison table

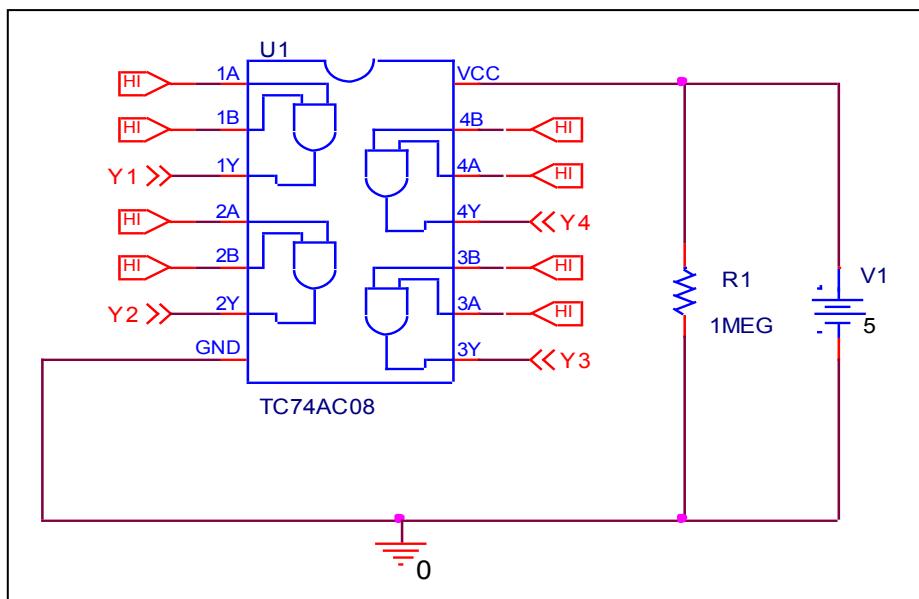
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
H	L	L	L	0

Truth Table

Circuit simulation result



Evaluation circuit

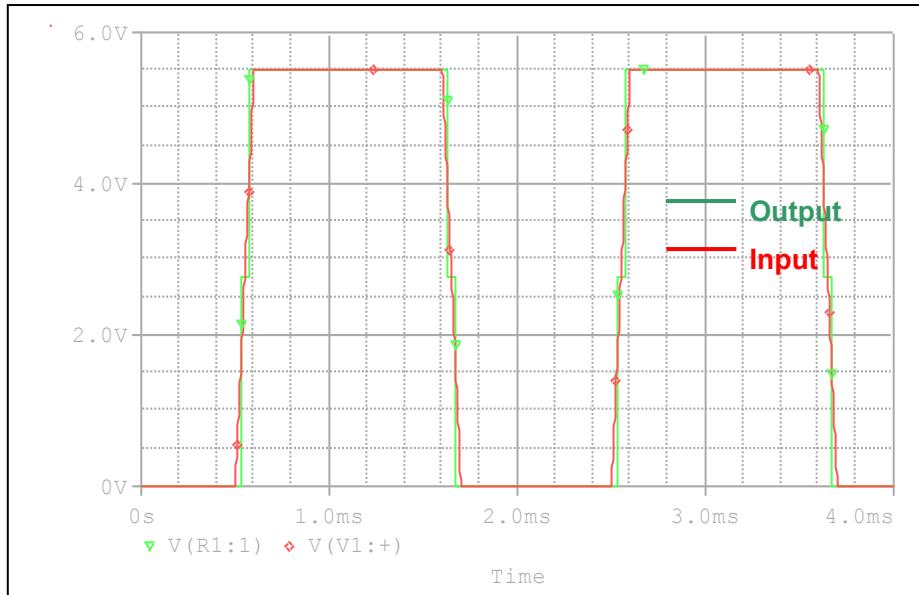


Comparison table

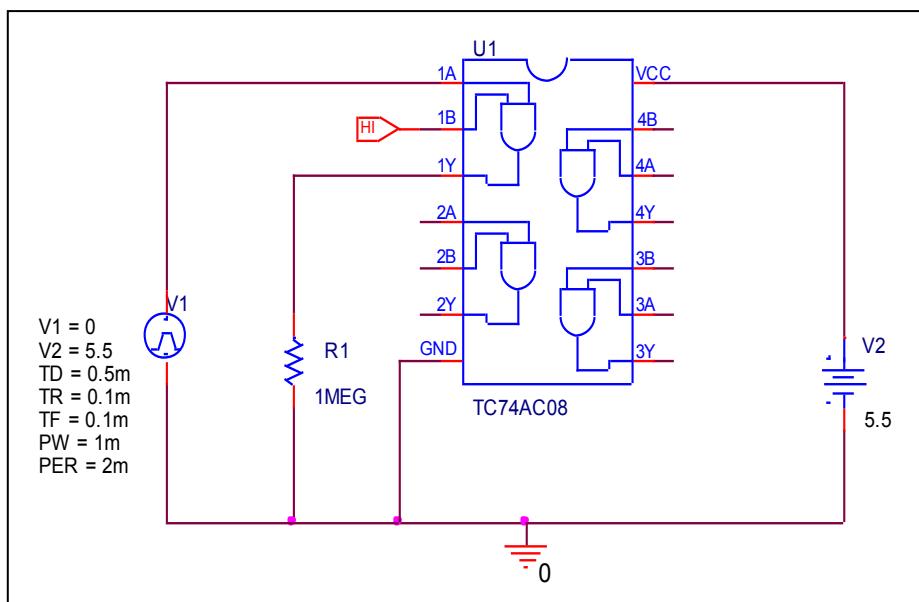
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
H	H	H	H	0

High Level and Low Level Input Voltage

Circuit simulation result



Evaluation circuit

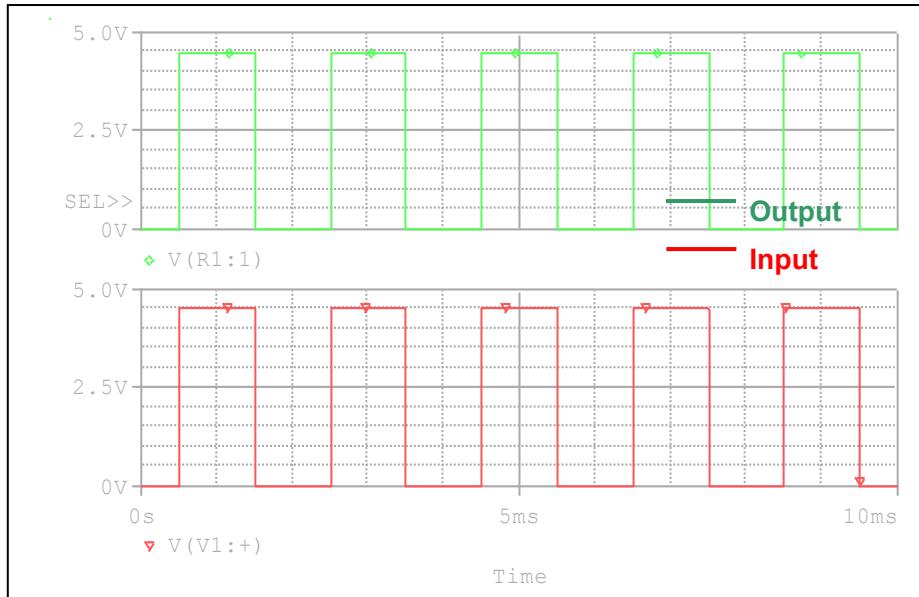


Comparison table

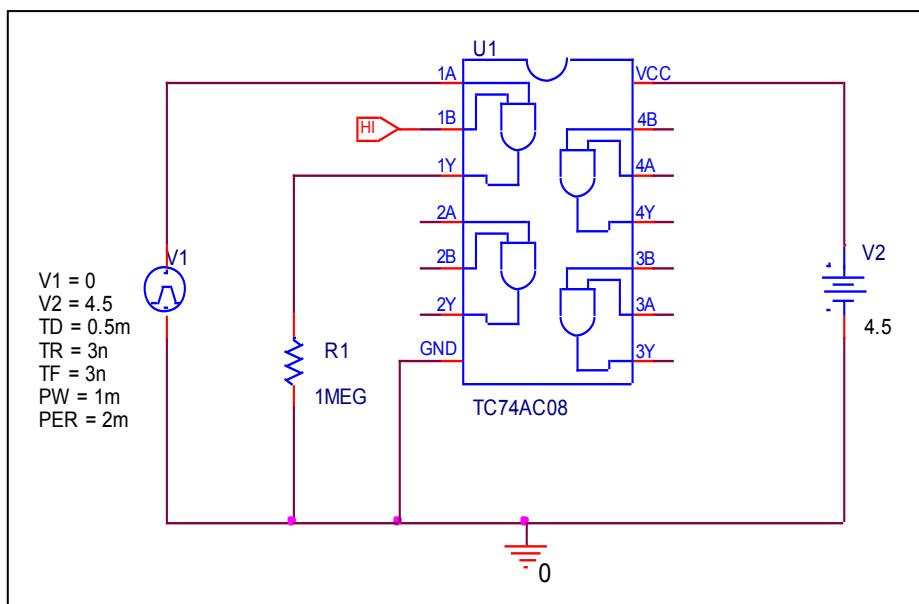
V_{CC} = 5.5V	Measurement	Simulation	%Error
V_{IH} (V)	3.85	3.9328	2.151
V_{IL} (V)	1.65	1.6445	-0.333

High Level and Low Level Output Voltage

Circuit simulation result



Evaluation circuit

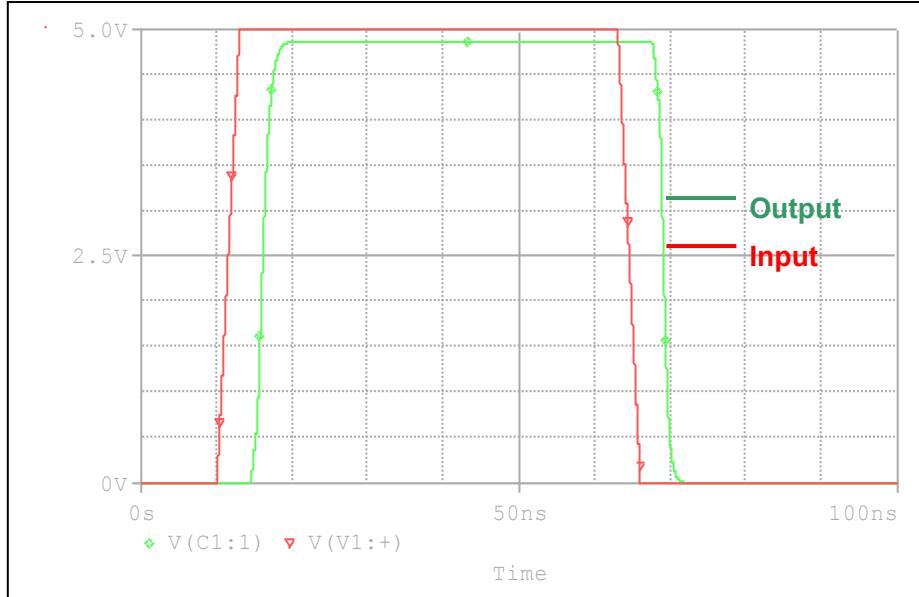


Comparison table

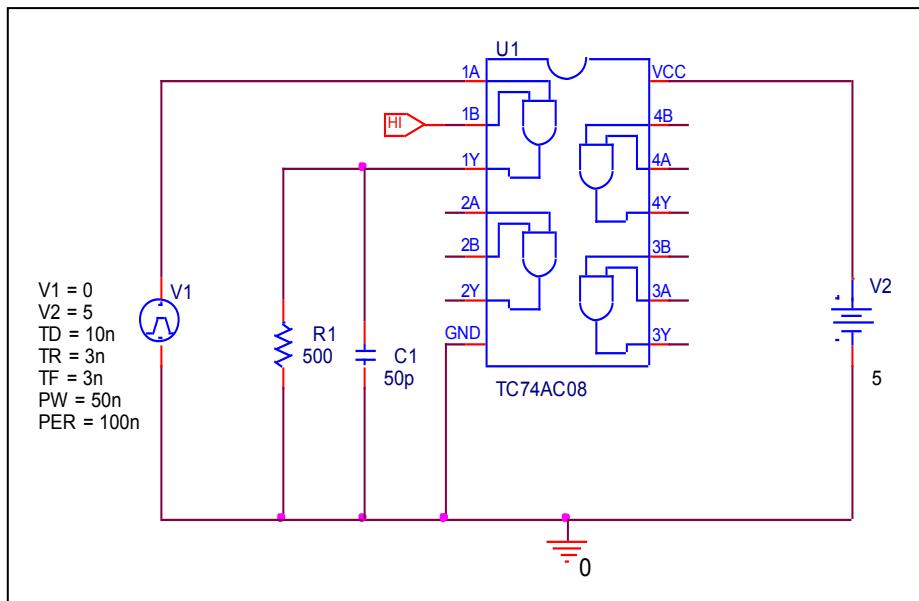
V_{CC} = 4.5V	Measurement	Simulation	%Error
V_{OH} (V)	4.5	4.4994	-0.013
V_{OL} (V)	0	0	0

Propagation Delay Time

Circuit simulation result



Evaluation circuit



Comparison table

$C_L = 50\text{pF}, R_L = 500\Omega, T_r = T_f = 3\text{ns}$	Measurement	Simulation	%Error
$t_{pLH} (\text{ns})$	4.5	4.5592	1.316
$t_{pHL} (\text{ns})$	4.5	4.5633	1.407